


<b>Search Notes</b>  	<b>Application/Control No.</b>  10553920	<b>Applicant(s)/Patent Under Reexamination</b>  KEVENAAR ET AL.
	<b>Examiner</b>  JAY P PATEL	<b>Art Unit</b>  2619

SEARCHED			
Class	Subclass	Date	Examiner
370	389, 392	8/1/2008	JPP
370	389, 392	12/30/2008	JPP

SEARCH NOTES		
Search Notes	Date	Examiner
East keyword search	8/1/2008	JPP
East keyword search((USPGPUB, USPTO, USOCR, FPRS, DERWENT, EPO, JPO; IEEE Xplorer search)	12/30/2008	JPP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	East Interference Search	12/30/2008	JPP

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